

<b>Notice of References Cited</b>	Application/Control No. 10/825,673	Applicant(s)/Patent Under Reexamination ENDO ET AL.	
	Examiner CHIA-WEI A. CHEN	Art Unit 2622	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,887,107	12-1989	Nakamura et al.	396/75
*	B	US-6,978,089	12-2005	Nomura et al.	396/75
*	C	US-4,969,719	11-1990	Bradshaw et al.	349/116
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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